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DATA SHEET

COMPOUND FIELD EFFECT POWER TRANSISTOR μ PA1556A

N-CHANNEL POWER MOS FET ARRAY SWITCHING TYPE

V V

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DESCRIPTION

The $\mu\text{PA1556A}$ is N-channel Power MOS FET Array that built in 4 circuits designed for solenoid, motor and lamp driver.

FEATURES

- 4 V driving is possible
- Large Current and Low On-state Resistance $I_{D(pulse)} = \pm 20 \text{ A}$ $R_{DS(on)} = 0.20 \Omega \text{ TYP.} (V_{GS} = 10 \text{ V})$ $R_{DS(on)} = 0.25 \Omega \text{ TYP.} (V_{GS} = 4 \text{ V})$
- Low Capacitance Ciss = 700 pF TYP.
- Gate Protecter built in.
- 2.54 mm Pitch (0.1 inch)

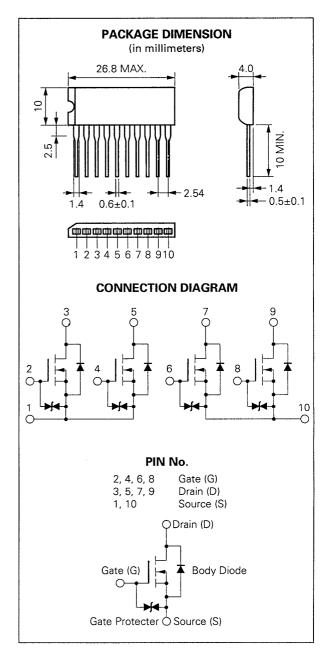
ORDERING INFORMATION

Part Number	Package	Quality Grade
μΡΑ1556AH	10 Pin SIP	Standard

Please refer to "Quality grade on NEC Semiconductor Devices" (Document number IEI-1209) published by NEC Corporation to know the specification of quality grade on the devices and its recommended applications.

ABSOLUTE MAXIMUM RATINGS (Ta = 25 °C)					
Drain to Source Voltage	VDSS	100			
Gate to Source Voltage (AC)	Vgss	±20			
Cata ta Causa Malta a (DO)	11	00 40			

	Gate to Source Voltage (DC)	VGSS	+20,-10	V
	Drain Current (DC)	D(DC)	±5.0	A/unit
	Drain Current (pulse)	ID(pulse)*	±20	A/unit
	Total Power Dissipation (4 circ	uits)		
	<tc 25="" =="" °c=""></tc>	Pt1	28	W
	Total Power Dissipation (4 circ	uits)		
	<ta 25="" =="" °c=""></ta>	Pt2	3.5	W
	Storage Temperature	Tstg -	-55 to +150) °C
	Junction Temperature	Tj	150	°C
*	PW ≦ 10 µs, Duty Cycle ≦ 1 %			



Document No. IC-3348 Date Published January 1994 M Printed in Japan

CHARACTERISTIC	SYMBOL	MIN.	TYP.	MAX.	UNIT	TEST CONDITIONS	
Drain Leakage Current	loss			10	μΑ	Vds = 100 V, Vgs = 0	
Gate to Source Leakage Current	lgss			±10	μΑ	$V_{GS} = \pm 20 \text{ V}, \text{ VDS} = 0$	
Gate to Source Cutoff Voltage	VGS(off)	1.0		2.5	V	Vps = 10 V, lp = 1 mA	
Forward Transfer Admittance	yfs	4.0			S	Vps = 10 V, Ip = 3 A	
Drain to Source On-state Resistance	RDS(on)1		0.20	0.25	Ω	Vgs = 10 V, Id = 3 A	
Drain to Source On-state Resistance	RDS(on)2		0.25	0.33	Ω	Vgs = 4 V, Id = 3 A	
Input Capacitance	Ciss		700		pF	V _{DS} = 10 V V _{GS} = 0 f = 1.0 MHz	
Output Capacitance	Coss		200		pF		
Reverse Transfer Capacitance	Crss		30		pF		
Turn-On Delay Time	td(on)		35		ns	Ib = 3 A VGS = 10 V Vcc = 50 V	
Rise Time	tr		60		ns		
Turn-Off Delay Time	td(off)		800		ns	$R_{L} = 17 \ \Omega, R_{in} = 10 \ \Omega$ See Fig. 1	
Fall Time	tf		200		ns		
Total Gate Charge	QG		17		nC	Vgs = 10 V ID = 5 A VDD = 80 V	
Gate to Source Charge	Qgs		2.5		nC		
Gate to Drain Charge	Qgd		4		nC	See Fig. 2	
Diode Forward Voltage	VF(S-D)		1.0		V	IF = 5 A, VGS = 0	
Reverse Recovery Time	trr		120		ns	IF = 5 A, VGS = 0 di/dt = 50 A/μs	
Reverse Recovery Charge	Qrr		230		nC		

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Fig. 1 Switching Time Test Circuit

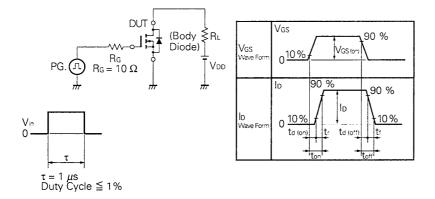
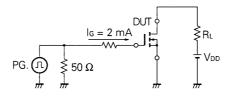
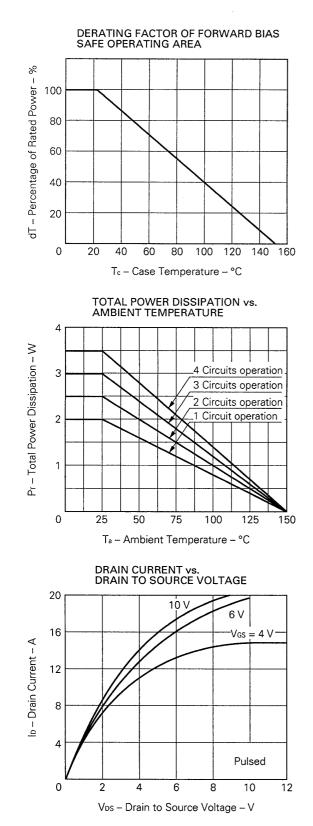
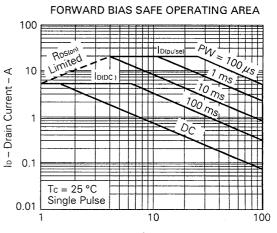


Fig. 2 Gate Charge Test Circuit



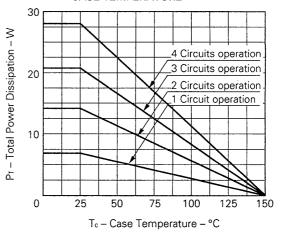
TYPICAL CHARACTERISTICS (Ta = 25 °C)



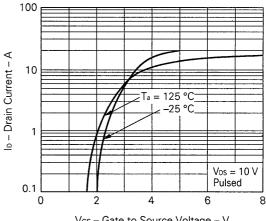




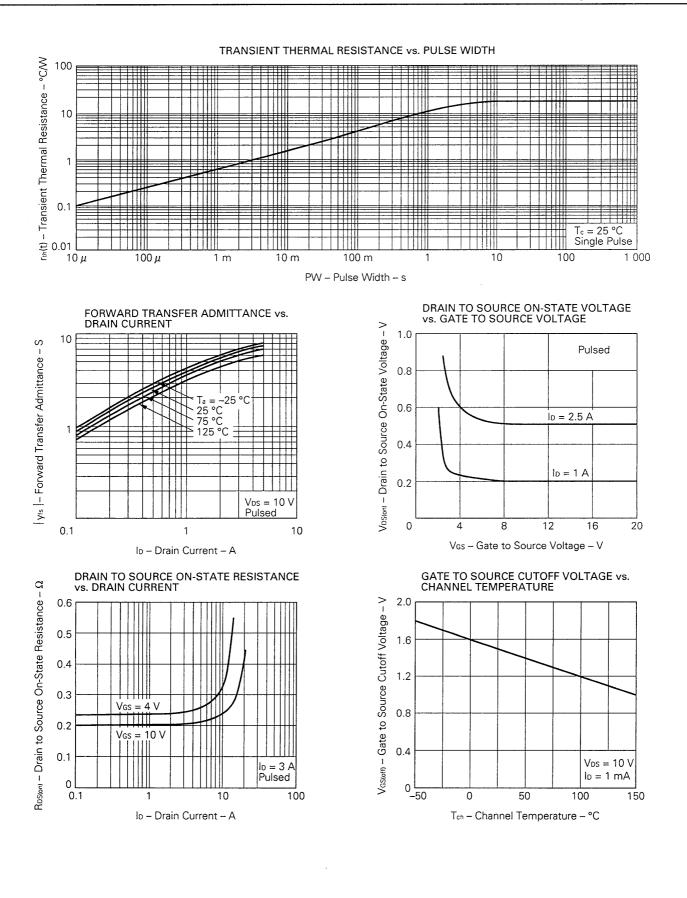
TOTAL POWER DISSIPATION vs. CASE TEMPERATURE



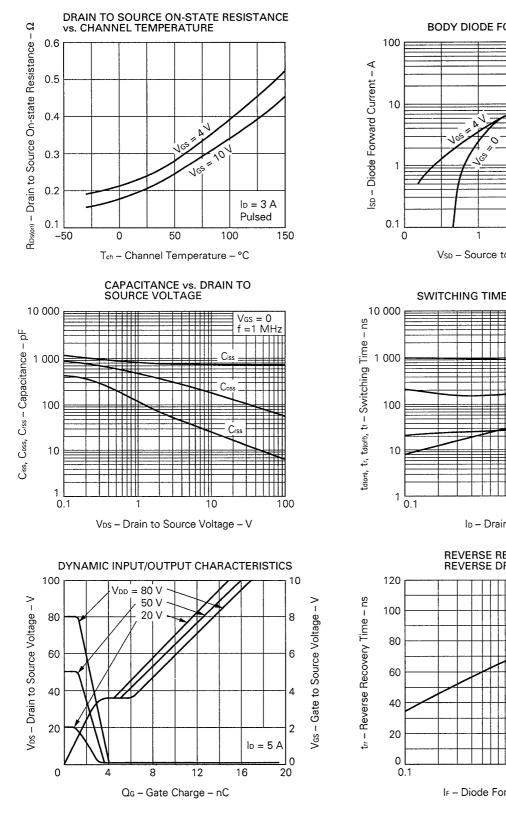




Vgs - Gate to Source Voltage - V

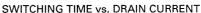


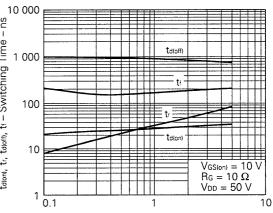
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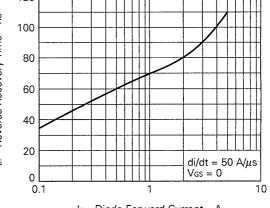
Ta = 25 °C Pulsed 2 3 Vsp – Source to Drain Voltage – V





ID - Drain Current - A

REVERSE RECOVERY TIME vs. REVERSE DRAIN CURRENT



IF - Diode Forward Current - A

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Reference

Document name	Document No.
Quality control of NEC semiconductors devices.	TEI-1202
Quality control guide of semiconductors devices.	MEI-1202
Assembly manual of semiconductors devices.	IEI-1207
Safe operating area of Power MOS FET	TEA-1034
Appication circuit using Power MOS FET	TEA-1035

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